

## CoolSiC™ 1700V SiC Trench MOSFET Silicon Carbide MOSFET

#### **Features**

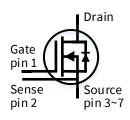
- Revolutionary semiconductor material Silicon Carbide
- Optimized for fly-back topologies
- 12V/0V gate-source voltage compatible with most fly-back controllers
- Very low switching losses
- Benchmark gate threshold voltage, V<sub>GS(th)</sub> = 4.5V
- Fully controllable dV/dt for EMI optimization

#### **Benefits**

- Reduction of system complexity
- Directly drive from fly-back controller
- Efficiency improvement and cooling effort reduction
- Enabling higher frequency

## **Potential applications**

- Energy generation
  - Solar string inverter
  - Solar Central inverter
- Industrial power supplies
  - Industrial UPS
  - Industrial SMPS
- Infrastructure Charger
  - Charger













#### **Product validation**

Qualified for industrial applications according to the relevant tests of JEDEC 47/20/22

Note: the source and sense pins are not exchangeable, their exchange might lead to malfunction recommended for forward operation mode only

Table 1 Key Performance and Package Parameters

Туре	<b>V</b> <sub>DS</sub>	$T_D$ $T_C = 25^{\circ}C, R_{th(j-c,max)}$	$R_{DS(on)}$ $T_{vj} = 25^{\circ}C, I_{D} = 1A, V_{GS} = 12V$	$T_{ m vj,max}$	Marking	Package
IMBF170R1K0M1	1700V	5.2A	$1000 \text{m}\Omega$	175°C	170M11K0	PG-TO263-7

Datasheet

Please read the Important Notice and Warnings at the end of this document

## **CoolSiC™ 1700V SiC Trench MOSFET**



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## CoolSiC<sup>™</sup> 1700V SiC Trench MOSFET



#### **Maximum ratings**

## 1 Maximum ratings

For optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Parameter	Symbol	Value	Unit
Drain-source voltage, <i>T</i> <sub>vj</sub> ≥ 25°C	$V_{ m DSS}$	1700	V
DC drain current for $R_{\text{th(j-c,max)}}$ , limited by $T_{\text{vjmax}}$ , $V_{\text{GS}} = 12V$ ,			
$T_C = 25$ °C	I <sub>D</sub>	5.2	Α
$T_{\rm C} = 100^{\circ}{\rm C}$		3.7	
Pulsed drain current, $t_p$ limited by $T_{vjmax}$ , $V_{GS} = 12V$	I <sub>D,pulse</sub> <sup>1</sup>	13.3	А
Gate-source voltage <sup>2</sup>			
Max transient voltage, < 1% duty cycle	$V_{GS}$	-1020	V
Recommended turn-on gate voltage	$V_{GS,on}$	1215	V
Recommended turn-off gate voltage	$V_{GS,off}$	0	
Power dissipation, limited by $T_{v_{jmax}}$			
$T_{\rm C} = 25^{\circ}{\rm C}$	$P_{tot}$	68	W
$T_{C} = 100$ °C		34	
Virtual junction temperature	$T_{\rm vj}$	-55175	°C
Storage temperature	$T_{\rm stg}$	-55150	°C
Soldering temperature		250	0.0
Reflow soldering (MSL1 according to JEDEC J-STD-020)	$T_{sold}$	260	°C

<sup>&</sup>lt;sup>1</sup> verified by design

<sup>&</sup>lt;sup>2</sup> **Important note:** The selection of positive and negative gate-source voltages impacts the long-term behavior of the device. The design guidelines described in <u>Application Note AN2018-09</u> must be considered to ensure sound operation of the device over the planned lifetime.

## CoolSiC™ 1700V SiC Trench MOSFET



## Thermal resistances

## 2 Thermal resistances

#### Table 3

Davamatav	Complete	Conditions	Value			Unit
Parameter	Symbol		min.	typ.	max.	
MOSFET thermal resistance, junction – case	$R_{th(j-c)}$		-	1.7	2.2	K/W
Thermal resistance, junction – ambient	$R_{th(j-a)}$	leaded	-	-	62	K/W

## **CoolSiC™ 1700V SiC Trench MOSFET**



#### **Electrical Characteristics**

## **3** Electrical Characteristics

## 3.1 Static characteristics

Table 4 Static characteristics (at  $T_{vj}$  = 25°C, unless otherwise specified)

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Drain-source on-state	R <sub>DS(on)</sub>	$V_{GS} = 12V, I_{D} = 1A,$				
resistance		$T_{\rm vj} = 25^{\circ} \rm C$	-	1000	-	
		T <sub>vj</sub> = 100°C	-	1416	-	mΩ
		$T_{\rm vj} = 175^{\circ}{\rm C}$	-	2037	-	11122
		$V_{GS} = 15V, I_{D} = 1A,$				
		T <sub>vj</sub> = 25°C	-	809	880	
Gate-source threshold voltage	$V_{GS(th)}$	(tested after 1 ms pulse at $V_{GS}$ = 20V)				
		$I_{\rm D} = 1.1  {\rm mA}, \ V_{\rm DS} = V_{\rm GS}$				V
		T <sub>vj</sub> = 25°C	3.5	4.5	5.7	
		T <sub>vj</sub> =175°C	-	3.6	-	
Zero gate voltage drain	I <sub>DSS</sub>	$V_{\rm GS}$ = 0V, $V_{\rm DS}$ = 1700V				
current		T <sub>vj</sub> = 25°C	-	0.4	11	μΑ
		$T_{\rm vj} = 175^{\circ}{\rm C}$	-	6	-	
Gate-source leakage	$I_{GSS}$	$V_{GS} = 20V, V_{DS} = 0V$	-	-	100	nA
current		$V_{GS} = -10V, V_{DS} = 0V$	-	-	-100	nA
Transconductance	$g_{fs}$	$V_{\rm DS} = 20 \text{V}, I_{\rm D} = 1 \text{A}$	-	0.42	-	S
Internal gate resistance	$R_{G,int}$	$f = 1$ MHz, $V_{AC} = 25$ mV	-	35	-	Ω

## **CoolSiC™ 1700V SiC Trench MOSFET**



### **Electrical Characteristics**

## 3.2 Dynamic characteristics

## Table 5 Dynamic characteristics (at $T_{vj} = 25^{\circ}$ C, unless otherwise specified)

Davamatav	Symbol	Conditions	Value			Unit
Parameter		Conditions	min.	typ.	max.	Onic
Input capacitance	C <sub>iss</sub>		-	275	-	
Output capacitance	Coss	$V_{DD} = 1000 \text{V}, V_{GS} = 0 \text{V},$ $f = 1 \text{MHz}, V_{AC} = 25 \text{mV}$ $V_{DD} = 1000 \text{V}, I_{D} = 1 \text{A},$ $V_{GS} = 0/12 \text{V}, \text{turn-on pulse}$	-	7.2	-	pF
Reverse capacitance	$C_{rss}$		-	0.7	-	
C <sub>oss</sub> stored energy	Eoss		-	1.3	-	μJ
Total gate charge	$Q_{G}$		-	5	-	
Gate to source charge	$Q_{GS,pl}$		-	1.5	-	nC
Gate to drain charge	$Q_{GD}$		-	1.6	-	

#### **CoolSiC™ 1700V SiC Trench MOSFET**



#### **Electrical Characteristics**

## 3.3 Switching characteristics

### Table 6 Switching characteristics, Inductive load <sup>3</sup>

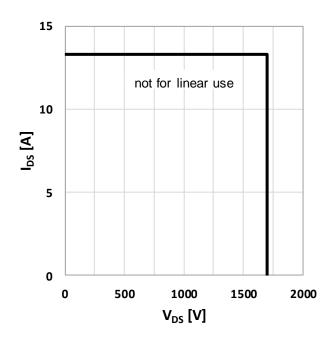
Parameter	Symbol	Conditions	Value	Value		
			min.	typ.	max.	
<b>MOSFET Characteristics,</b>	<i>T</i> <sub>vj</sub> = 25°C					
Turn-on delay time	t <sub>d(on)</sub>	$V_{\rm DD} = 1000  \text{V}, I_{\rm D} = 1  \text{A},$	-	19	-	
Rise time	t <sub>r</sub>	$V_{\rm GS} = 0/12 \text{V}, R_{\rm G,ext} = 22 \Omega,$ $L_{\sigma} = 40 \text{nH},$ diode: body diode at $V_{\rm GS} = 0 \text{V}$	-	14	-	
Turn-off delay time	$t_{\sf d(off)}$		-	20	-	ns
Fall time	t <sub>f</sub>		-	22	-	
Turn-on energy	Eon		-	31	-	
Turn-off energy	$E_{ m off}$	see Fig. E	-	7	-	μJ
Total switching energy	E <sub>tot</sub>		-	37	-	

MOSFET Characteristics, $T_{vj} = 175^{\circ}C$						
Turn-on delay time	$t_{\sf d(on)}$	$V_{DD} = 1000 \text{V}, I_D = 1 \text{A},$	-	16	-	
Rise time	t <sub>r</sub>	$V_{\rm GS} = 0/12 \text{V}, R_{\rm G,ext} = 22 \Omega,$ $L_{\sigma} = 40 \text{nH},$ diode:	-	11	-	
Turn-off delay time	$t_{ m d(off)}$		-	23	-	ns
Fall time	t <sub>f</sub>		-	23	-	
Turn-on energy	Eon	body diode at $V_{GS} = 0V$	-	33	-	
Turn-off energy	$E_{ m off}$	see Fig. E	-	8	-	μJ
Total switching energy	$E_{\rm tot}$		-	41	-	

 $<sup>^3</sup>$  The chip technology was characterized up to 200 kV/ $\mu$ s. The measured dV/dt was limited by measurement test setup and package. In applications, e.g. fly-back topology, the switching behavior highly depends on the circuitry (transformer, snubber...), the switching loss in the application will be different from the datasheet value.

#### **Electrical characteristic diagrams**

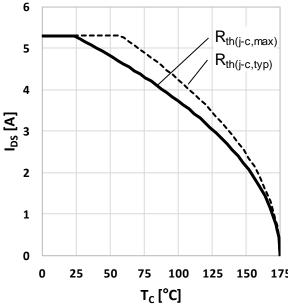
#### **Electrical characteristic diagrams** 4



80  $R_{\text{th(j-c,max)}}$ 70  $R_{th(j-c,typ)}$ 60 50 40 30 20 10 0 25 50 75 100 125 150 175 0 T<sub>C</sub> [°C]

Safe operating area (SOA) Figure 1  $(V_{GS} = 0/12V, T_c = 25^{\circ}C, T_i \le 175^{\circ}C)$ 

Power dissipation as a function of case Figure 2 temperature limited by bond wire  $(P_{\text{tot}} = f(T_{\text{C}}))$ 



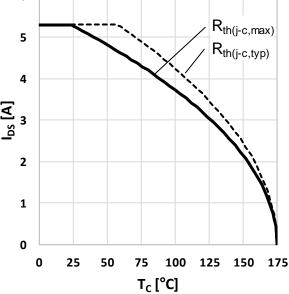


Figure 3 **Maximum DC drain to source current** as a function of case temperature limited by bond wire  $(I_{DS} = f(T_C))$ 

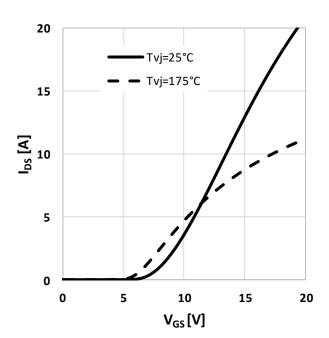
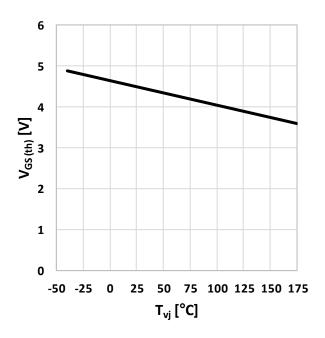


Figure 4 **Typical transfer characteristic**  $(I_{DS} = f(V_{GS}), V_{DS} = 20V, t_{P} = 20\mu s)$ 

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### **Electrical characteristic diagrams**



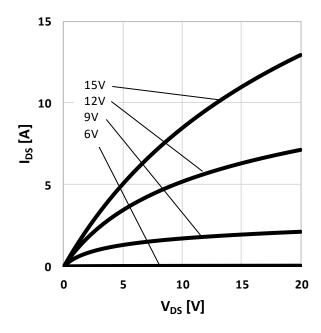
2 000 1 750 R<sub>DS (ON)</sub> [mOhm] 1 500 1 250 1 000 **750** VGS = 12V 500 •••• VGS = 15V 250 0 -50 -25 25 50 75 100 125 150 175 0  $T_{vj}$  [°C]

Figure 5 Typical gate-source threshold voltage as a function of junction temperature

 $(V_{GS(th)} = f(T_{vj}), I_{DS} = 1.1 \text{mA}, V_{GS} = V_{DS})$ 

Figure 6 Typical on-resistance as a function of junction temperature

$$(R_{DS(on)} = f(T_{vj}), I_{DS} = 1A)$$



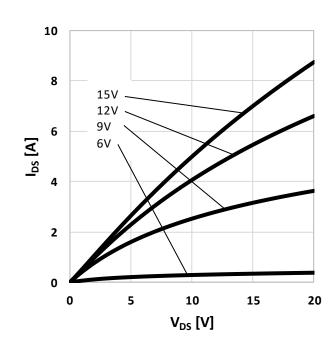


Figure 7 Typical output characteristic,  $V_{GS}$  as parameter

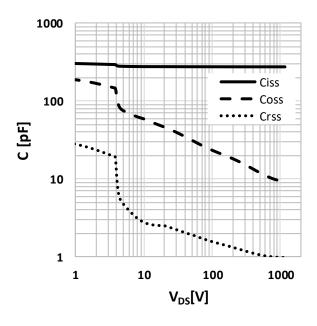
$$(I_{DS} = f(V_{DS}), T_{vj} = 25^{\circ}C, t_{P} = 20\mu s)$$

Figure 8 Typical output characteristic,  $V_{GS}$  as parameter

$$(I_{DS} = f(V_{DS}), T_{vj} = 175^{\circ}C, t_{P} = 20 \mu s)$$

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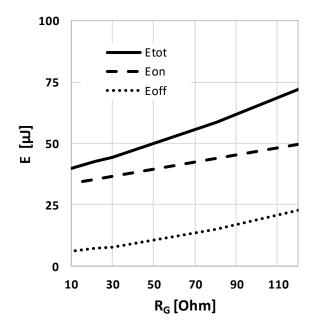
#### **Electrical characteristic diagrams**



15 10 E S 5 0 0 0 2 4 6 Q<sub>G</sub>[nC]

Figure 9 Typical capacitance as a function of drain-source voltage  $(C = f(V_{DS}), V_{GS} = 0V, f = 1MHz)$ 

Figure 10 Typical gate charge  $(V_{GS} = f(Q_G), I_{DS} = 1A, V_{DS} = 1000V, turn-on pulse)$ 



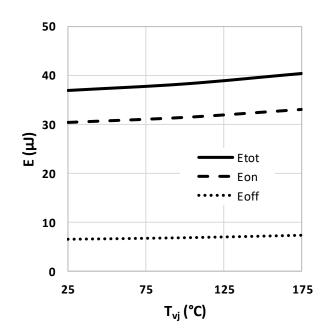


Figure 11 Typical switching energy losses as a function of gate resistance  $(E = f(R_{G,ext}), V_{DD} = 1000V, V_{GS} = 0V/12V,$ 

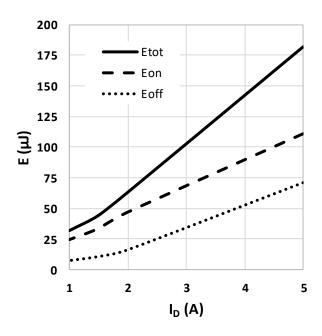
 $(E = f(R_{G,ext}), V_{DD} = 1000V, V_{GS} = 0V/12V,$   $I_D = 1A, T_{vj} = 175$ °C, ind. load, test circuit in Fig. E, diode: body diode at  $V_{GS} = 0V$ )

Figure 12 Typical switching energy losses as a function of junction temperature  $(E = f(T_{vj}), V_{DD} = 1000V, V_{GS} = 0V/12V,$   $R_{G,ext} = 22\Omega, I_D = 1A$ , ind. load, test circuit in Fig. E, diode: body diode at

 $V_{GS} = 0V$ 

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#### **Electrical characteristic diagrams**



To 30 50 70 90 110 R<sub>G</sub> [Ohm]

Figure 13 Typical switching energy losses as a function of drain-source current

 $(E = f(I_{DS}), V_{DD} = 1000V, V_{GS} = 0V/12V,$  $R_{G,ext} = 22\Omega, T_{vj} = 175^{\circ}C$ , ind. load, test circuit in Fig. E, diode: body diode at  $V_{GS} = 0V$ )

Figure 14 Typical switching times as a function of gate resistor

 $(t = f(R_{G,ext}), V_{DD} = 1000V, V_{GS} = 0V/12V,$  $I_D = 1A, T_{vj} = 175^{\circ}C$ , ind. load, test circuit in Fig. E, diode: body diode at  $V_{GS} = 0V$ )

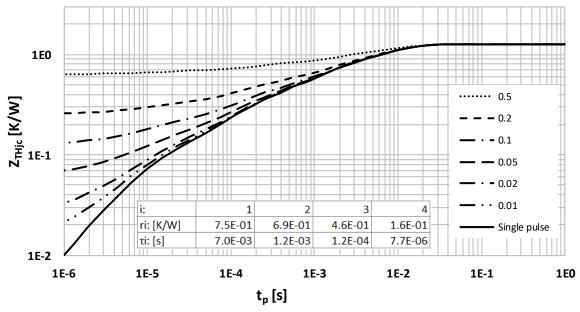


Figure 15 Max. transient thermal resistance (MOSFET)

 $(Z_{\text{th}(j-c,max)} = f(t_P)$ , parameter  $D = t_p/T$ , thermal equivalent circuit in Fig. D)



**Package drawing** 

## 5 Package drawing

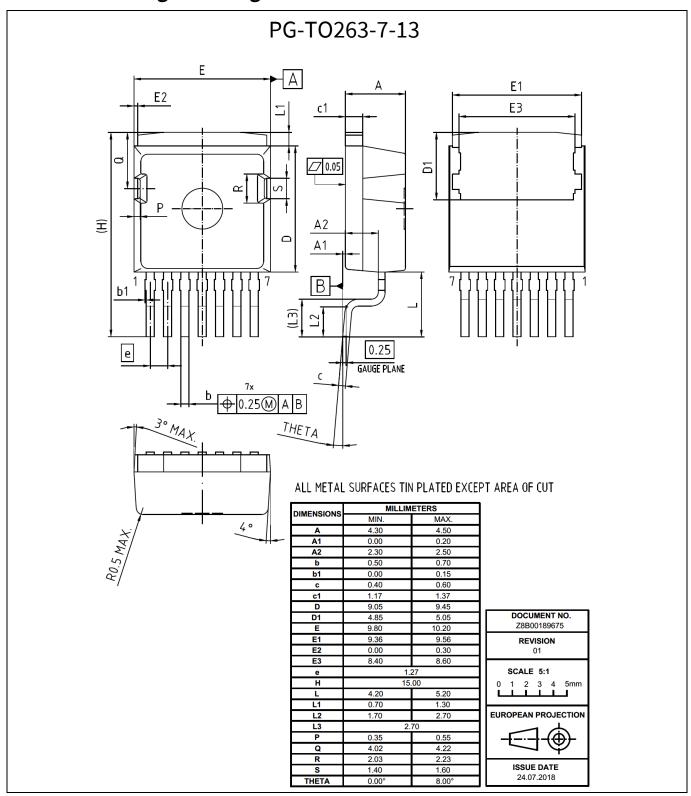


Figure 16 Package drawing

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#### **Test conditions**

## **6** Test conditions

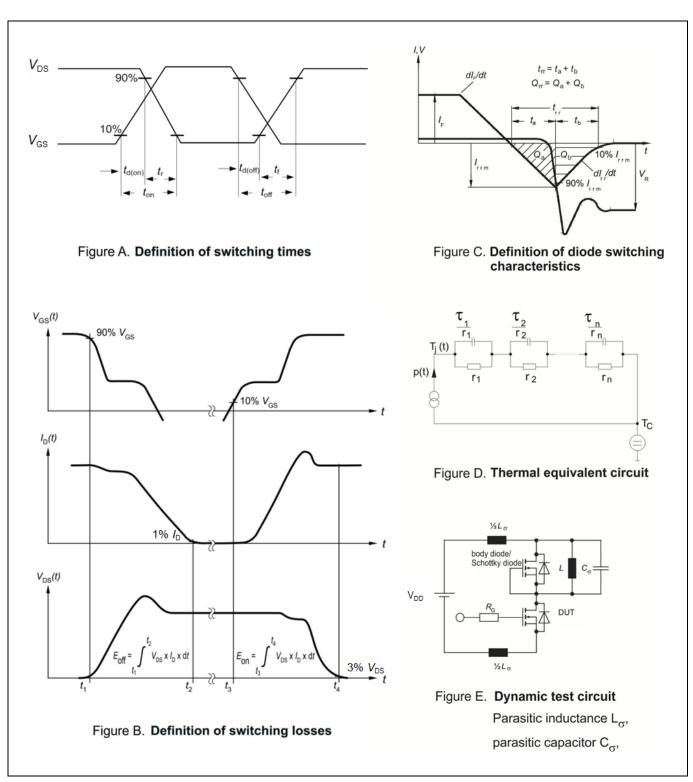


Figure 17 Test conditions

## **CoolSiC™ 1700V SiC Trench MOSFET**



**Revision history** 

## **Revision history**

Document version	Date of release	Description of changes
2.1	2020-04-27	Final Datasheet

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